Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/689,901	YACH, DAVID P.	
Examiner	Art Unit	
Yicun Wu	2165	

	SEARCHED				
Class	Subclass	Date	Examiner		
707	1-10, 100- 104.1 200-206	6/15/2006	ΥW		
375	240	6/15/2006	YW		
341	107	6/15/2006	YW		
	1				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	<u> </u>				
1					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
inventor search (double patenting) uspto uspgpub epo jpo ibmtech derwent	6/15/2006	ΥW	
acm ieee citeseer internet Search stratagy attached	6/15/2006	YW	
consulted Apu mofiz	6/15/2006	YW	